Abstract

Memories are the most dominating blocks present on a chip. All types of chips contain embedded memories such as a ROM, SRAM, DRAM, and flash memory. Testing of these memories is a very tedious and challenging job as area over head, testing time and cost of the test play an important role. Embedded memories are occupying a significant portion of the System-on-chip area. Because of this trend and the nature of memory's small geometry, implementing a good memory testing strategy is one of the most significant decision making. Built-In Self-Test, a design technique which uses parts of the circuit to test the circuit itself is used for testing. BIST controller is used to control the total testing process of the memory.

References

- "March SS: A Test for All Static Simple RAM Faults," by Said Hamdioui, Ad J.
van de Goor, Mike Rodgers.

Index Terms

Computer Science
Electronics

Keywords

Microcode BIST controller; Memory Built in self test (MBIST); Memory Built in self
repair (MBISR)